THIRD ECHELON TEST SET

DESCRIPTION

The Third Echelon Test Set (TETS) will detect and diagnose weapon system failures in line-replaceable units and circuit card assemblies for a variety of communication-electronic, electro-optic, and ground weapon systems. The electro-optic version provides the ability to test, diagnose, and align weapon systems such as forward-looking infrared sights and laser range finders. The Third Echelon Test Set provides this capability in both manual and automatic modes. Automatic mode is accomplished by using a Test Program Set. Manual mode is accomplished by using the Stand Alone Instrument Panel.

OPERATIONAL IMPACT

The MAGTF has numerous systems and equipment that contain electronicprinted circuit cards. The Third Echelon Test System provides a man-portable test capability that can be used to fault-isolate and repair LRU's down to the faulty circuit card assembly. This capability enables maintenance personnel to repair more equipment forward and send only failed items to rear areas for required repairs.

As weapon systems become more complex, the amount of MAGTF equipment containing secondary repairables with replaceable electronic components is increasing. The Marine Corps has recognized the need for and has fielded automated test equipment to support maintenance of equipment containing linereplaceable units. TETS significantly enhances intermediate maintenance support capabilities.



PROGRAM STATUS

The first two TETS production lots were completed in 2002. Testing for the electro-optic version of TETS started in December 2003 and should be completed in April 2004. Production deliveries of the TETS EO version began in June 2003 at the rate of four systems per month. TETS will begin production of an additional 95 systems in 2004. This production will continue through 2008.

PROCUREMENT PROFILE:

FY 04

FY 05

Quantity:

11

16

DEVELOPER/MANUFACTURER

Prime contractor: ManTech Test Systems, Chantilly, VA